Application/Control No. Applicant(s)/Patent Under Reexamination 08/973,424 IEHISA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Phillip Nguyen 2828 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY Α US-4,791,631 12-1988 Baumert et al. 372/22 US-В US-C US-D US-Ε F US-G USн US-US-US-J US-Κ US-L М US-FOREIGN PATENT DOCUMENTS Document Number Date Country Country Code-Number-Kind Code Name Classification MM-YYYY JP 04-259275 Ν 09-1992 Japan 0 Р Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

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^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.